

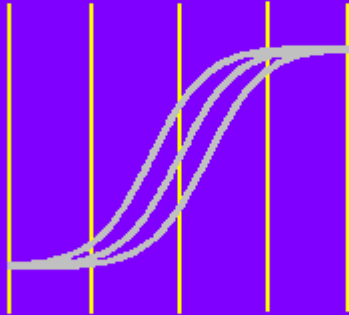
# Introduction to Rasch Measurement

Edited By

Everett V. Smith, Jr.

Richard M. Smith

## Introduction to Rasch Measurement



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JAM Press is pleased to announce that the new book, *Introduction to Rasch Measurement: Theory, Models, and Applications*, is now available. The book is available in soft cover (\$47, ISBN 0-9755351-1-0) and hard cover (\$59, ISBN 0-9755351-0-2). Postage and handling are additional. Information on ordering the book (689 pages) is found on the reverse of this announcement and also available at the website for the *Journal of Applied Measurement*, [www.jampress.org](http://www.jampress.org). Please go to the JAM Press Books page on that website and scroll down to the new books section. A PDF of the JAM Press order form is also available for printing on that web page. *Introduction to Rasch Measurement: Theory, Models, and Applications* contains 24 chapters, written by the leading experts in Rasch measurement, which discuss all aspects of family of Rasch measurement models. A listing of the chapters can be found below.

### I. THEORY

1. An Overview of the Family of Rasch Measurement Models  
*Benjamin Wright, University of Chicago*  
*Magdalena Mo Ching Mok, Hong Kong Institute of Education*
2. Estimation Methods for Rasch Measures  
*J. Michael Linacre, University of Sunshine Coast*
3. Rasch Model Estimation: Further Topics  
*J. Michael Linacre, University of Sunshine Coast*
4. Fit Analysis in Latent Trait Measurement Models  
*Richard Smith, Data Recognition Corporation*
5. Evidence of the Reliability of Measures and Validity of Measure Interpretation: A Rasch Measurement Perspective  
*Everett Smith, University of Illinois at Chicago*
6. On Choosing a Model for Measuring  
*Mark Wilson, University of California, Berkeley*
7. Controversy and the Rasch Model: A Characteristic of Incompatible Paradigms?  
*David Andrich, Murdoch University*
8. Understanding Resistance to the Data-Model Relationship in Rasch's Paradigm: A Reflection for the Next Generation  
*David Andrich, Murdoch University*

### II. MODELS

9. Substantive Scale Construction  
*Mark H. Stone, Adler School of Professional Psychology*

10. Rasch Measurement: The Dichotomous Model  
*Randall Schumacker, University of North Texas*
11. Optimizing Rating Scale Category Effectiveness  
*J. Michael Linacre, University of Sunshine Coast*
12. Partial Credit Model and Pivot Anchoring  
*Rita Bode, Rehabilitation Institute of Chicago*
13. Construction of Measures from Many-Facet Data  
*J. Michael Linacre, University of Sunshine Coast*  
*Benjamin Wright, University of Chicago*
14. An Introduction to Multidimensional Measurement using Rasch Models  
*Derek C. Briggs, University of Colorado*  
*Mark Wilson, University of California, Berkeley*
15. Metric Development and Score Reporting in Rasch Measurement  
*Everett Smith, University of Illinois at Chicago*

### III. APPLICATIONS

16. Equating and Item Banking with the Rasch Model  
*Edward Wolfe, Michigan State University*
17. Detecting Item Bias with the Rasch Model  
*Richard Smith, Data Recognition Corporation*
18. Rasch Techniques for Detecting Bias in Performance Assessments: An Example Comparing the Performance Native and Non-Native Speakers on a Test of Academic English  
*Catherine Elder, University of Auckland*  
*Tim McNamara, University of Melbourne*  
*Peter Congdon, Victorian Curriculum and Assessment Authority*

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| <p>19. Objective Standard Setting (or Truth in Advertising)<br/><i>Gregory Stone, University of Toledo</i></p> <p>20. Detected and Measuring Rater Effects using Many-Facet Rasch Measurement: Part I</p> <p>21. Detected and Measuring Rater Effects using Many-Facet Rasch Measurement: Part II<br/><i>Carol Myford, University of Illinois at Chicago</i><br/><i>Edward Wolfe, Michigan State University</i></p> <p>22. Detecting and Evaluating the Impact of Multidimensionality using Item Fit Statistics and Principal Component Analysis of Residuals<br/><i>Everett Smith, University of Illinois at Chicago</i></p> | <p>23. Computer Adaptive Testing<br/><i>Richard Gershon, Northwestern University</i></p> <p>24. The Rasch Model, Additive Conjoint Measurement, and New Models of Probabilistic Measurement Theory<br/><i>George Karabatsos, University of Illinois at Chicago</i></p> |
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